

Dkt. 01196

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

BINH VU THIEN et al

PCT

Serial No.: 09/926,489

Filed: November 13, 2001

For: METHOD AND DEVICE FOR EXTRACTION OF ELECTRODES IN A
VACUUM AND EMISSION CATHODES FOR SUCH DEVICE



INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner of Patents and Trademarks
Washington, D.C. 20231

Sir:

Submitted herewith are copies of the references
cited in the International Search Report which are listed on
the attached Form PTO-1449.

Respectfully submitted,

Ira J. Schultz
Registration No. 28666

Form PTO-1449				ATTY DOCKET NO. 01196				APPLICATION NO. 09/926,489					
INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)								APPLICANT Binh VU THIEN et al					
								FILING DATE November 13, 2001				GROUP	
U.S. PATENT DOCUMENTS													
EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	3	0	9	8	1	6	8	3/59	Aigrain				
	3	1	1	4	0	7	0	12/58	Stratton				
	3	1	2	1	8	0	9	2/64	Atalla				
	3	9	1	6	2	2	7	10/75	Mize				
	5	2	6	6	8	6	7	11/30	Sakurai				
	5	3	5	9	2	5	7	10/94	Bunch et al				
FOREIGN PATENT DOCUMENTS													
	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES NO	
	0	6	9	6	0	4	3	2/96	EP				
		9	6	4	7	6	0	8/50	FR				
	1	2	2	5	6	7	5	7/60	FR				
	05	3	4	2	9	8	3	12/93	JP Abstract				
	08	0	0	7	7	4	6	1/96	JP Abstract				
	98	0	6	1	3	5		2/98	WO				
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)													
		XP-002126517 "Ballistic Electron Emission Microscopy Study of Schottky Contacts on 6H- and 4H-SiC", Im et al, Applied Physics Letters, Vol. 72, No. 7, 1998, pp. 839-841.											
		XP-004081165 "Electron emission Characteristics of Metal/Diamond Field Emitters", Sugino et al, Elsevier Science S.A., Vol. 6, No. 5-7, pp. 889- 892.											
		XP-000749210 "Theory and Experimental Results of a New Diamond Surface- Emission Cathode", Geis et al, The Lincoln Laboratory Journal, Vol. 10, No. 1, pp. 3-18.											
EXAMINER								DATE CONSIDERED					
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.													